

Notic of R ferences Cit d

Application/Control No.

09/319,699

Applicant(s)/Patent Under
Reexamination
LIPPERT ET AL.

Examiner

Douglas A Wille

Art Unit

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,323,031	06-1994	Shohji et al.	257/198
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Sokolic et al., Modelling Base Transpaort Properties of npn SiGe HBT Semiconductor Conference 9-12 Oct. 1996.
	V	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.